

Notice of References Cited	Application/Control No. 10/820,421	Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner John Juba, Jr.	Art Unit 2872	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0201889 A1	10-2004	Wang et al.	359/486
	B	US-6,122,103	09-2000	Perkins et al.	359/486
	C	US-4,289,381	09-1981	Garvin et al.	427/163.1
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zhaoning Yu, et al., "Reflective polarizer based on a stacked double-layer subwavelength metal grating structure fabricated using nanoimprint lithography", Appl. Phys. Lett., Vol. 77, no. 7, pp. 927-929, 14 AUG 2000.
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.